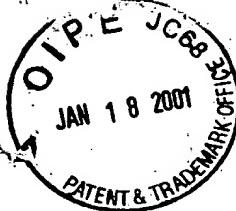


Attorney Docket No. 18940/36899
PATENT



Stevenson
#3
2-12-01

JAN 18 2001

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Matsumoto Toshiyuki, Yakabe Masami, Hirota Yoshihiro
Serial No.: 09/703,845 Group: 2858
Filed: November 2, 2000 Examiner:
For: CAPACITANCE MEASUREMENT METHOD OF MICRO STRUCTURES
OF INTEGRATED CIRCUITS

SUBMISSION UNDER 37 C.F.R. 1.56, 1.97 & 1.98
INFORMATION DISCLOSURE STATEMENT

Honorable Assistant Commissioner
for Patents
Washington, D.C. 20231

Sir:

To comply with the duty of disclosure set forth in 37 CFR 1.56, the prior art listed on the attached PTO-1449 is submitted herewith to the Examiner for consideration in connection with the examination of the above-identified application.

The Commissioner is hereby authorized to charge any additional fees which may be required, or credit any overpayment to Account No. 02-1010 (18940/36899).

Respectfully submitted,

BARNES & THORNBURG

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JAN 18 2001

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| FORM PTO-1449 | | U.S. DEPARTMENT OF COMMERCE PATENTS AND TRADEMARK OFFICE | ATTY DOCKET NO. 18940/36899 | SERIAL NO. 09/703,845 |
| LIST OF DOCUMENTS CITED BY APPLICANT (Use several sheets if necessary) | | APPLICANT | M. Toshiyuki, Y. Masami, H. Yoshihiro | |
| | | FILING DATE | GROUP | |
| | | November 2, 2000 | 2858 | |

JAN 18 2001
U.S. PATENT & TRADEMARK OFFICE

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| EXAMINER INITIAL | | DOCUMENT NUMBER | DATE | NAME | CLASS | SUBCLASS | FILING DATE IF APPROPRIATE |
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OTHER PRIOR ART (Including Author, Title, Date Pertinent Pages, Etc.)

| | | |
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| <i>TY</i> | AQ | <i>An On-Chip, Attofarad Interconnect Charge-Based Capacitance Measurement (CBCM Technique)</i> , J.C. Chen, B.W. McGaughy, D. Sylvester, C. Hu, Department of EECS, University of California Berkeley, 1996 |
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| EXAMINER: | | <i>T.R. L</i> | |
| | | DATE CONSIDERED: | <i>5/22/02</i> |
| *EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. | | | |

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